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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

#3/A  
KD  
9-30-01

Applicant(s): SHIMODA et al

Serial No.: 09/783,604

Filed: February 15, 2001

For: Method For Analyzing Circuit Pattern Defects And A Technology Center 2600 System Thereof

Group: 2621

Examiner:

RECEIVED

AUG 22 2001

**PRELIMINARY AMENDMENT**

Assistant Commissioner for Patents  
Washington, D.C. 20231

August 20, 2001

Sir:

The following preliminary amendments and remarks are respectfully submitted in connection with the above-identified application.

**IN THE TITLE:**

Please amend the title to read as follows.

--A Method And System For Analyzing Circuit Pattern Defects--.

**IN THE SPECIFICATION:**

Please replace the original specification with the attached Substitute Specification.

**IN THE ABSTRACT OF THE DISCLOSURE:**

Please replace the original abstract with the attached abstract.